

CoolMOS[™] **Power Transistor**

Features

- \bullet Worldwide best $R_{\it DS\,,on}$ in TO220
- Lowest figure of merit $R_{\text{ON}} x Q_{\text{g}}$
- Ultra low gate charge
- Extreme dv/dt rated
- · High peak current capability
- Pb-free lead plating; RoHS compliant; Halogen free for mold compound
- Qualified for industrial grade applications according to JEDEC¹⁾

CoolMOS CP is designed for:

- Hard & soft switching SMPS topologies
- CCM PFC for ATX, Notebookadapter & PDP and LCD TV
- PWM Stages for Server, Adapter

Туре	Package	Marking
IPP50R140CP	PG-TO220	5R140P

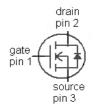
Maximum ratings, at T_j =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I _D	T _C =25 °C	23	А
		T _C =100 °C	15	
Pulsed drain current ²⁾	/ _{D,pulse}	T _C =25 °C	56	
Avalanche energy, single pulse	E _{AS}	/ _D =9.3 A, V _{DD} =50 V	616	mJ
Avalanche energy, repetitive $t_{AR}^{(2),3)}$	E _{AR}	/ _D =9.3 A, V _{DD} =50 V	0.93	
Avalanche current, repetitive $t_{AR}^{(2),3)}$	I _{AR}		9.3	А
MOSFET dv/dt ruggedness	d <i>v</i> /d <i>t</i>	V _{DS} =0400 V	50	V/ns
Gate source voltage	V_{GS}	static	±20	V
		AC (f>1 Hz)	±30	
Power dissipation	P_{tot}	T _C =25 °C	192	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 150	°C
Mounting torque		M3 and M3.5 screws	60	Ncm

Product Summary

V _{DS} @T _{jmax}	550	٧
R _{DS(on),max}	0.140	Ω
$Q_{g,typ}$	48	nC







Maximum ratings, at $T_{\rm j}$ =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous diode forward current	Is	Т _С =25 °С	14	А
Diode pulse current ²⁾	/ _{S,pulse}	7 _C -23 G	56	
Reverse diode dv/dt ⁴⁾	dv/dt		15	V/ns

Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Thermal characteristics						
Thermal resistance, junction - case	R _{thJC}		1	-	0.65	K/W
Thermal resistance, junction - ambient	$R_{ m thJA}$	leaded	1	-	62	
Soldering temperature, wavesoldering only allowed at leads	T_{sold}	1.6 mm (0.063 in.) from case for 10 s	-	-	260	°C

Electrical characteristics, at T_j =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	V _{GS} =0 V, I _D =250 μA	500	-	ı	V
Gate threshold voltage	$V_{GS(th)}$	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 0.93 \text{ mA}$	2.5	3	3.5	
Zero gate voltage drain current	/ _{DSS}	V _{DS} =500 V, V _{GS} =0 V, T _j =25 °C	1	1	2	μA
		V _{DS} =500 V, V _{GS} =0 V, T _j =150 °C	-	20	-	
Gate-source leakage current	I _{GSS}	V _{GS} =20 V, V _{DS} =0 V	-	-	100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =10 V, I _D =14 A, T _j =25 °C	1	0.13	0.14	Ω
		V _{GS} =10 V, I _D =14 A, T _j =150 °C	-	0.32	-	
Gate resistance	R _G	f=1 MHz, open drain	-	2.2	-	Ω



Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	C iss	V _{GS} =0 V, V _{DS} =100 V,	-	2540	-	pF
Output capacitance	C oss	f=1 MHz	-	110	-	
Effective output capacitance, energy related ⁵⁾	C _{o(er)}	V _{GS} =0 V, V _{DS} =0 V	-	110	-	
Effective output capacitance, time related ⁶⁾	C _{o(tr)}	to 400 V	-	230	-	
Turn-on delay time	t _{d(on)}		-	35	-	ns
Rise time	t _r	V _{DD} =400 V, V _{GS} =10 V, I _D =14 A,	-	14	-	1
Turn-off delay time	$t_{d(off)}$	$R_{\rm G}$ =10 V, $I_{\rm D}$ =14 A, $R_{\rm G}$ =12.2 Ω	-	80	-	1
Fall time	t _f		-	8	-	
Gate Charge Characteristics						
Gate to source charge	Q _{gs}		-	11	-	nC
Gate to drain charge	Q_{gd}	V _{DD} =400 V, I _D =14 A,	-	15	-	1
Gate charge total	Qg	V _{GS} =0 to 10 V	-	48	64	1
Gate plateau voltage	V _{plateau}		-	5.2	-	V
Reverse Diode						
Diode forward voltage	V _{SD}	V _{GS} =0 V, I _F =14 A, T _j =25 °C	-	0.9	1.2	V
Reverse recovery time	t _{rr}		-	400	-	ns
Reverse recovery charge	Q _{rr}	V _R =400 V, I _F =I _S , d <i>i</i> _F /d <i>t</i> =100 A/μs	-	5.6	-	μC
Peak reverse recovery current	I _{rrm}]	-	26	_	А

¹⁾ J-STD20 and JESD22

 $^{^{2)}}$ Pulse width $t_{
m p}$ limited by $T_{
m j,max}$

 $^{^{3)}}$ Repetitive avalanche causes additional power losses that can be calculated as $P_{\rm AV}$ = $E_{\rm AR}$ *f.

 $^{^{4)} \ \}textit{I}_{\text{SD}} \!\! \leq \!\! \textit{I}_{\text{D}}, \ d\textit{i} / dt \! \leq \! 200 \text{A/} \mu \text{s}, \ V_{\text{DClink}} \!\! = \!\! 400 \text{V}, \ V_{\text{peak}} \!\! < \!\! V_{\text{(BR)DSS}}, \ T_{j} \!\! < \!\! T_{j\text{max}}, \ \text{identical low and high side switch}$

 $^{^{5)}}$ $C_{\rm o(er)}$ is a fixed capacitance that gives the same stored energy as $C_{\rm oss}$ while $V_{\rm DS}$ is rising from 0 to 80% $V_{\rm DSS}$.

 $^{^{6)}}$ $C_{\rm o(tr)}$ is a fixed capacitance that gives the same charging time as $C_{\rm oss}$ while $V_{\rm DS}$ is rising from 0 to 80% $V_{\rm DSS}$.



1 Power dissipation

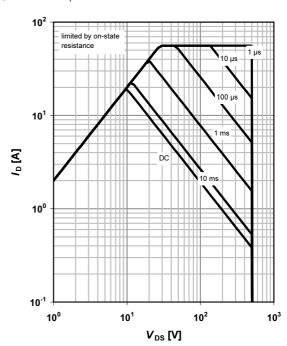
 P_{tot} =f(T_{C})

200 180 160 140 120 P_{tot} [M] 100 80 60 40 20 0 100 125 150 175 0 25 *T* _C [°C]

2 Safe operating area

 I_D =f(V_{DS}); T_C =25 °C; D=0

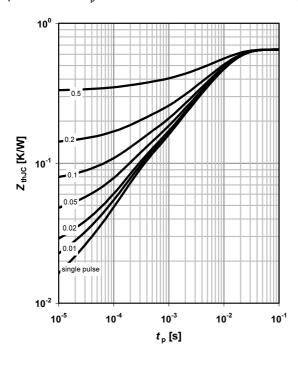
parameter: t_p



3 Max. transient thermal impedance

 $Z_{(thJC)} = f(t_p);$

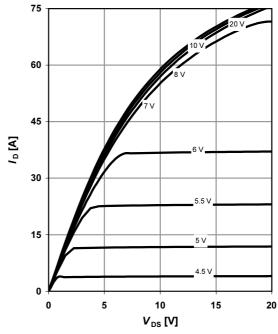
parameter: D=t_p/T



4 Typ. output characteristics

 $I_D = f(V_{DS}); T_j = 25 °C$

parameter: V_{GS}

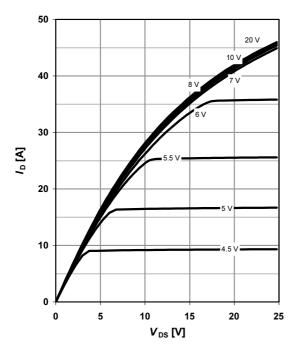




5 Typ. output characteristics

 $I_D = f(V_{DS}); T_j = 150 °C$

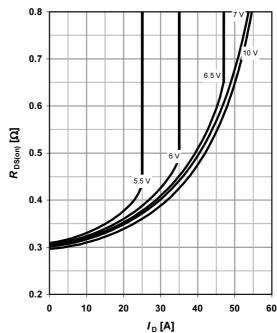
parameter: V_{GS}



6 Typ. drain-source on-state resistance

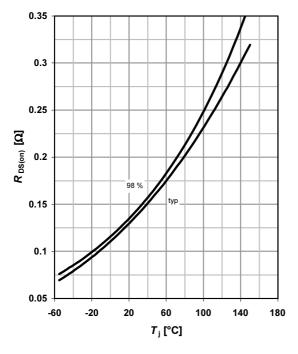
 $R_{DS(on)}$ =f(I_D); T_j =150 °C

parameter: V_{GS}



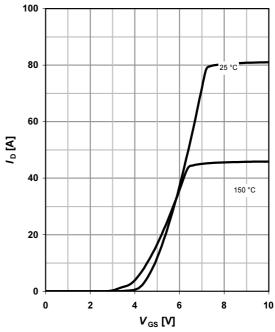
7 Drain-source on-state resistance

 $R_{DS(on)}$ =f(T_j); I_D =14 A; V_{GS} =10 V



8 Typ. transfer characteristics

 $I_{\rm D}$ =f($V_{\rm GS}$); $|V_{\rm DS}|$ >2 $|I_{\rm D}|R_{\rm DS(on)max}$ parameter: $T_{\rm j}$

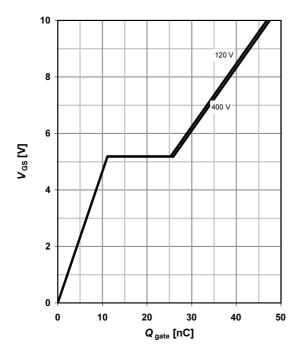




9 Typ. gate charge

 $V_{\rm GS}$ =f(Q _{gate}); $I_{\rm D}$ =14 A pulsed

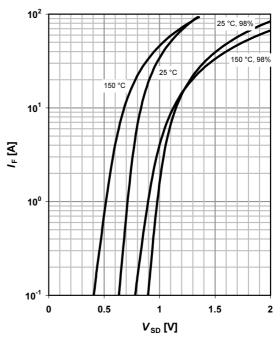
parameter: $V_{\rm DD}$



10 Forward characteristics of reverse diode

 $I_{\mathsf{F}} = \mathsf{f}(V_{\mathsf{SD}})$

parameter: T_j

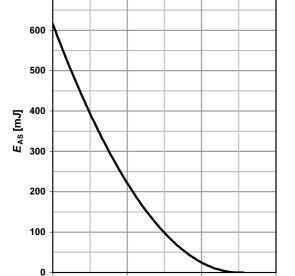


11 Avalanche energy

700

25

 E_{AS} =f(T_{j}); I_{D} =9.3 A; V_{DD} =50 V

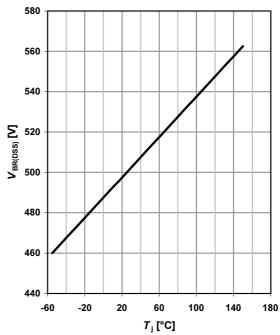


125

*T*_j [°C]

12 Drain-source breakdown voltage

 $V_{BR(DSS)}$ =f(T_j); I_D =0.25 mA



175

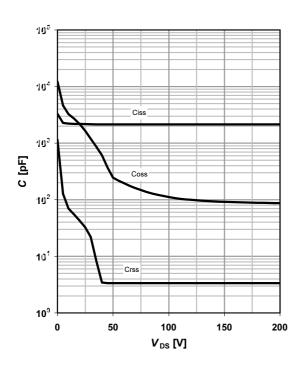


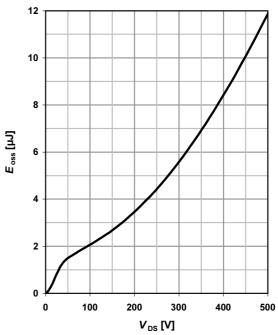
13 Typ. capacitances

$C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$

14 Typ. Coss stored energy

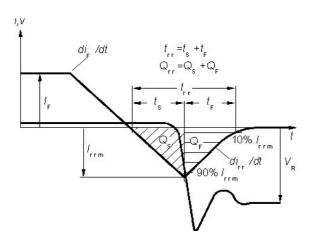
$$E_{oss} = f(V_{DS})$$





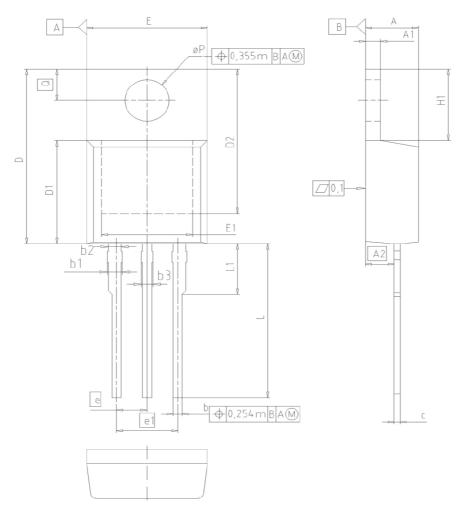


Definition of diode switching characteristics





PG-TO220-3-1/PG-TO220-3-21: Outlines



DIM	MILLI	METERS	INC	HES
DIM	MIN	MAX	MIN	MAX
Α	4.30	4.57	0.169	0.180
A1	1.17	1.40	0.046	0.055
A2	2.15	2.72	0.085	0.107
b	0.65	0.86	0.026	0.034
b1	0.95	1.40	0.037	0.055
b2	0.95	1.15	0.037	0.045
b3	0.65	1.15	0.026	0.045
С	0.33	0.60	0.013	0.024
D	14.81	15.95	0.583	0.628
D1	8.51	9.45	0.335	0.372
D2	12.19	13.10	0.480	0.516
E	9.70	10.36	0.382	0.408
E1	6.50	8.60	0.256	0.339
е	2	.54	0.1	100
e1	5	6.08	0.2	200
N		3		3
H1	5.90	6.90	0.232	0.272
L	13.00	14.00	0.512	0.551
L1	-	4.80	-	0.189
øΡ	3.60	3.89	0.142	0.153
Q	2.60	3.00	0.102	0.118

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2.5 0 2.5 5mm
EUROPEAN PROJECTION
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